IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Patent Application

Applicant(s):	Michael J. Berman
Serial No.:	09/553,140
Confirm. No.:	4444
Filing Date:	April 20, 2000
Art Unit:	2624
Examiner:	Aaron W. Carter
Title:	Determination of Film Thickness During Chemical Mechanical Polishing

AMENDMENT AND RESPONSE TO OFFICE ACTION

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

In response to the outstanding non-final Office Action dated October 16, 2009, Applicant respectfully requests reconsideration of the above-identified application in view of the amendments and remarks herein.